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APPLICATION NO.	F	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/707,844	,844 11/08/2000		Hidetoshi Ishida	0819-448	9493
22204	7590	09/25/2006		EXAMINER	
NIXON PI			FARAHANI, DANA		
401 9TH ST SUITE 900	401 9TH STREET, NW SUITE 900				PAPER NUMBER
WASHINGTON, DC 20004-2128				2891	
				DATE MAILED: 09/25/2000	6

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)
	09/707,844	ISHIDA ET AL.
Office Action Summary	Examiner	Art Unit
	Dana Farahani	2891
The MAILING DATE of this communication a	ppears on the cover sheet w	vith the correspondence address
A SHORTENED STATUTORY PERIOD FOR REF WHICHEVER IS LONGER, FROM THE MAILING - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by state Any reply received by the Office later than three months after the may earned patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNI 1.136(a). In no event, however, may a od will apply and will expire StX (6) MO tute, cause the application to become A	ICATION. reply be timely filed  NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).
Status		
1)	his action is non-final.  vance except for formal mat	
Disposition of Claims		
<ul> <li>4)  Claim(s) 11-18 is/are pending in the application 4a) Of the above claim(s) is/are withd</li> <li>5)  Claim(s) is/are allowed.</li> <li>6)  Claim(s) 11-18 is/are rejected.</li> <li>7)  Claim(s) is/are objected to.</li> <li>8)  Claim(s) are subject to restriction and</li> </ul>	rawn from consideration.	
Application Papers		
9) ☐ The specification is objected to by the Examination The drawing(s) filed on <u>06 May 2005</u> is/are:  Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct of the theory of the the last of the l	a)⊠ accepted or b)□ objection described by accepted or b)□ objection is required if the drawing	nce. See 37 CFR 1.85(a). g(s) is objected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority documents.  2. Certified copies of the priority documents.  3. Copies of the certified copies of the papplication from the International Burents.  * See the attached detailed Office action for a limit of the papplication.	ents have been received. ents have been received in a riority documents have been eau (PCT Rule 17.2(a)).	Application No n received in this National Stage
Attachment(s)  1) Notice of References Cited (PTO-892)  2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  3) Information Disclosure Statement(s) (PTO/SB/08)  Paper No(s)/Mail Date	Paper No	Summary (PTO-413) o(s)/Mail Date Informal Patent Application

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### **DETAILED ACTION**

## Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 11-14, 17 and 18 are rejected under 35 U.S.C. 102(b) as being anticipated by Inoue (US Patent 5,151,770), previously cited.

Regarding claims 11, 14, 17 and 18, Inoue discloses in figure 1, a semiconductor device comprising:

A plurality of semiconductor elements, 24 and 26, formed on a semiconductor substrate 21, 27; and

A plurality of through holes, which are provided between two adjacent ones of the plurality of semiconductor elements and pass from a surface through the backside of the semiconductor substrate, which is GaAs (see figure 5, and col. 9, lines 29-32); and

a distance between two adjacent ones of the plurality of through holes (which is 100 microns. See col. 6, line 13) is smaller than a thickness of the semiconductor substrate (which is 500 mu plus the thickness of 21).

Regarding claim 12, the through holes are covered with a conductive material (see col. 8, lines 1-5).

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Regarding claim 13, the conductive material is electrically connected to a ground wiring layer 52 (figs. 4 and 5) provided on the surface of the backside of the substrate (see col. 8, lines 1-5).

3. Claims 15 and 16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Inoue as applied to claims 11-14 above, and further in view of Nakamura et al., hereinafter Nakamura (US Patent 6,229,209), previously cited.

Inoue discloses the limitations in the claims, as discussed above, except for a second group of through holes which are provided in electrodes of the plurality of semiconductor elements, pass from a surface through the backside of the substrate, and whose faces are covered with conductive material.

Nakamura discloses in figure 1, a second group of through holes 23 which are provided in electrodes of the semiconductor element 3, pass from a surface through the backside of the substrate 20, and whose faces are covered with conductive material 24 (see col. 6, lines 4-19). Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to make connection to the semiconductor devices of the Inoue in the fashion of the Nakamura reference (which would lead to their connection to the backside ground wiring 52), commonly known as flip chip structure, in order to make contacts to the semiconductor components of the Inoue, and provide a ground voltage reference for those devices. Flip chip configurations and their advantages, such as occupying less space and making secure contacts are well known in the art.

## Response to Arguments

4. Applicant's arguments with respect to the previously rejected claims have been considered but are most in view of the new ground(s) of rejection.

### Conclusion

5. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dana Farahani whose telephone number is (571)272-1706. The examiner can normally be reached on M-F 9:00AM - 5:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Bill Baumeister can be reached on (571)272-1722. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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B. WILLIAM BAUMEISTER
SUPERVISORY PATENT EXAMINER